


<b>Search Notes</b>  	<b>Application/Control No.</b>  10567000	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Jeffrey Lenihan	<b>Art Unit</b>  1796

SEARCHED			
Class	Subclass	Date	Examiner
525	63, 64, 69, 100, 191, 209, 210, 474	10/6/2008	/JL/
525	63, 64, 69, 100, 191, 209, 210, 471	4/21/2009	/JL/

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor Search in eDAN/PALM	10/6/2008	/JL/
See Attached EAST History	10/6/2008	/JL/
Online Search	10/6/2008	/JL/
updated EAST search	4/21/2009	/JL/
updated EAST history	11/3/2009	/JL/
updated EAST history	6/3/2010	/JL/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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